



# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

*(Multiple sheets used when necessary)*

SHEET 1 OF 3

Application No.	10/632,481
Filing Date	August 1, 2003
First Named Inventor	Talieh et al.
Art Unit	3723
Examiner	David Thomas
Attorney Docket No.	ASMNUT.012C1CP1

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
DST	1	669,923	03-1901	Grauert	
	2	3,888,050	06-1975	Elm	
	3	4,412,400	11-1983	Hammond	
	4	4,802,309	02-1989	Heynacher	
	5	5,245,796	09-1993	Miller et al.	
	6	5,335,453	08-1994	Baldy et al.	
	7	5,377,452	01-1995	Yamaguchi	
	8	5,377,453	01-1995	Pemeczky	
	9	5,429,733	07-1995	Ishida	
	10	5,489,235	02-1996	Gagliardi et al.	
	11	5,558,568	09-1996	Talieh et al.	
	12	5,650,039	07-1997	Talieh	
	13	5,679,212	10-1997	Kato et al.	
	14	6,692,947	12-1997	Talieh et al.	
	15	5,707,409	01-1998	Martin et al.	
	16	5,759,918	06-1998	Hoshizaki et al.	
	17	5,762,751	06-1998	Bleck et al.	
	18	5,770,521	06-1998	Pollock	
	19	5,807,165	09-1998	Uzoh et al.	
	20	5,810,964	09-1998	Shiraishi	
	21	5,851,136	12-1998	Lee	
	22	5,893,755	04-1999	Nakayoshi	
	23	5,899,798	05-1999	Trojan et al.	
	24	5,899,801	05-1999	Trolles et al.	
	25	5,908,530	06-1999	Hoshizak et al.	
	26	5,913,716	06-1999	Mucci et al.	
	27	5,951,368	09-1999	Watanabe et al.	
	28	5,951,377	09-1999	Vaughn et al.	
DST	29	5,961,372	10-1999	Shendon	

Examiner Signature

Date Considered

4/27/05

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**U.S. PATENT DOCUMENTS**

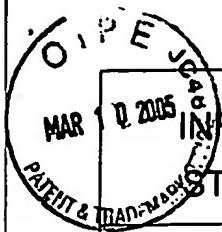
Examiner Initials	Cite No.	Document Number <i>Number - Kind Code (if known)</i> Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
1837	30	5,975,988	11-1999	Christianson	
	31	6,017,831	01-2000	Beardsley et al.	
	32	6,068,542	05-2000	Hosokai	
	33	6,110,025	08-2000	Williams et al.	
	34	6,113,479	09-2000	Sinclair et al.	
	35	6,129,540	10-2000	Hoopman et al.	
	36	6,135,859	10-2000	Tietz	
	37	6,136,715	10-2000	Shendon et al.	
	38	6,179,690	01-2001	Talieh	
	39	6,241,583	06-2001	White	
	40	6,302,767	10-2001	Tietz	
	41	6,312,319	11-2001	Donohue et al.	
	42	6,379,231	04-2002	Birang et al.	
	43	6,413,873	07-2002	Li et al.	
	44	6,419,559	07-2002	Gurusamy et al.	
	45	6,428,394	08-2002	Mooring et al.	
	46	6,439,978	08-2002	Jones et al.	
	47	6,464,571 B2	10-2000	Talieh et al.	
	48	6,468,139	10-2002	Talieh et al.	
	49	6,475,070	11-2002	White	
	50	6,500,056	12-2002	Krussel et al.	
	51	6,589,105 B2	07-2003	Young et al.	
	52	6,604,988 B2	08-2003	Talieh et al.	
	53	6,634,935 B2	10-2003	Young et al.	
	54	6,736,710 B2	05-2004	Osawa et al.	
1837	55	US 2002/0123298 A1	09-2002	Krussel et al.	

**FOREIGN PATENT DOCUMENTS**

Examiner Signature		Date Considered	
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Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>1</sup>
DT	56	DE 3113204	10-1982	Lambelet		
	57	EP 0 517 594	12-1992	Baldy		
	58	EP 0 941 806 A2	09-1999	Jew et al.		
	59	EP 1 025 955 A2	08-2000	Somekh et al.		
	60	WO 97/20660	06-1997	Shendon		
	61	WO 98/45090	10-1998	Donhue et al.		
	62	WO 99/22908	05-1999	Sommer		
	63	WO 00/32356	06-2000	Talieh		
DT	64	WO 02/02272 A1	01-2002	Owczarz et al.		

**NON PATENT LITERATURE DOCUMENTS**

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>
DT	65	STEIGERWALD et al., "Pattern geometry effects in the chemical-mechanical polishing of inlaid copper structures," October 1994, pp. 2842-2848.	

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